

# National Bureau of Standards

## Certificate

### Standard Reference Material 4266

#### Low-Energy Photon Standard

Radionuclide	Vanadium-49 (1)*
Source identification	4266-
K-x-ray emission rate	$s^{-1}$ per steradian (2)
Reference time	1200 EST January 19, 1981
Half life	$302.2 \pm 2.4 \text{ days}$ (3)
Measuring instrument	Low-geometry NaI(T]) x-ray detector (4)
Random uncertainty	0.6 percent (5)
Systematic uncertainty	1.7 percent (6)
Total uncertainty (Random plus Systematic)	2.3 percent
Photon emitting impurities (Activity ratios at reference time in percent)	22Na/49V: 0.26 88Y/49V: 0.02 57Co/49V: 6 x 10-3 65Zn/49V: <6 x 10-3 109Cd/49V: <3 x 10-3

This Standard Reference Material was prepared in the Center for Radiation Research, Nuclear Radiation Division, Radioactivity Group, D.D. Hoppes, Acting Group Leader.

Washington, D.C. 20234 February, 1981

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#### **FOOTNOTES**

- (1) The point source support is a 5.4-cm-diameter by 1-mm-thick aluminum annulus supporting a 0.006-cm-thick layer of polyester tape. The active source is a dried deposit of vanadium-49 as the chloride, covered with a layer of polyester film 0.00038-cm thick.
- (2) Emitted perpendicular to the plane of the source mount from the side with the source identification lettering. (Also see attached information sheet).
- (3) Measured at NBS with the low-geometry NaI(T1) x-ray detector system.
- (4) Efficiency determined with an  $^{55}$ Fe K-x-ray emission-rate primary standard source.
- (5) Half the 99-percent confidence interval of the mean (4.6 times the standard error computed from 5 measurements).
- (6) Linear sum of estimated uncertainty limits due to:
  - a) Extrapolations of photon spectra to zero energy 0.9 percent
  - b) Calculated absorption factors due to the Be windows and the Al reflector 0.5 percent
  - c) Geometry factor 0.3 percent